

Detector → Optical Coupling R&D (1/2)

- Feedhorn-standard
 - Baseline for feedhorn R&D
 - Mature technology, spline-profiled designs
 - * • Feedhorn-advanced profile design
 - Includes improved optimization, complex geometries
 - Gains: 5% mapping speed, systematic decrease of $\sim 10x$
 - Cost: 1 FTE for design
 - 75% likelihood of success (LOS), development path well-defined, target date: 2019
 - * • Feedhorn-dielectric feeds
 - Dielectrically-loaded feedhorns
 - Gains: 5% mapping speed, systematic decrease of $\sim 10x$, increase bandwidth from 2.3:1 to 3:1
 - Cost: 1 FTE for design (but could be same FTE as above)
 - 50% LOS, concept developed but some TD needed, target date: 2020
- * Highest rate of success and most bang for your buck

Detector → Optical Coupling R&D (2/2)

- Feedhorn-LF quadridge waveguide
 - Low frequency is only tenable band right now and would benefit most since the pixels are the largest
 - Gains: increase bandwidth from 2.3:1 to 3.5:1 with current designs, could push to 6:1 with further design work
 - Cost: 1 FTE for design, 0.5 FTE fab, 0.5 FTE testing
 - 50% LOS, some preliminary designs but need to prototype, target date: 2020
 - For this to be successful, we'd need to invest time and money in it now
- Feedhorn-improved coupling to microstrip
 - Better impedance matching between horn and microstrip could eliminate CPW and CPW-MS transition, slightly increase throughput (like Goddard detectors), requires Si vs SiN
 - Gains: <5% mapping speed
 - Cost: 1 FTE for design
 - 100% LOS, demonstrated on CLASS, target date: 2019
 - Not a high payoff for effort and difficulty of Si fab

I&T → Assembly Production → Horn Material/Production Testing (1/2)

- Si horn-Standard (Baseline)
 - DRIE+Photolithography production of stacked Si Arrays
 - 100 um horn to horn spacing
 - \$60k/array (includes labor of two full-time FTE)
 - Production rate: 7 weeks/6" array , ~5 wafers/day (single etch)
- * • Si horn-laser machining
 - Stacked Si array with laser-machined holes
 - Gains: production cost goes down to \$10k/array, could move to 12" array production, 10 wafers/day with only 1 FTE (saves several weeks/array and thus 2+ years in schedule)
 - R&D Cost: \$30k for test Si, 1 FTE
 - 75% likelihood of success (LOS), development is underway, target date: 2019

* Highest rate of success and most bang for your buck

I&T → Assembly Production → Horn Material/Production Testing (2/2)

- * • Al horns
 - Direct-machined, need to be careful about DTE between Si detector array, test machining tolerances, and test how closely horns can be spaced
 - Gains: production cost is \$10k/array, no FTE, 6 weeks for reamers then a few weeks/array to machine (saves several weeks/array and thus 2+ years in schedule), not limited to Si sizes, easy mounting
 - R&D Cost: \$10k for horn spacing and tolerancing tests
 - 100% likelihood of success (LOS), demonstrated on BLAST, target date: 2018
- Molybdenum horns
 - Direct-machined, test tolerances
 - Gains: All blue and red gains of Al, less DTE than Al, may allow closer horn spacing, production cost is \$40k/array for 1st array \$15k for identical arrays
 - R&D Cost: \$20k for horn spacing and tolerancing tests
 - 100% likelihood of success (LOS), demonstrated on BLAST, target date: 2018
- Alloy horns
 - Si-Al alloy, direct-machined (machining proprietary), only for LF, can't machine small enough for HF, MF+ more expensive than baseline
 - Gains: All blue gains of Al, less DTE than Al, 8 weeks/array, production cost is \$20k/array
 - R&D Cost: \$0, unless want to push outside of LF band
 - 100% likelihood of success (LOS), demonstrated on AdvACT LF, target date: 2018